

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re: Young-pil Kim et al.

Serial No.: 10/796,672

Filed: March 9, 2004

For: **Semiconductor Device Test Patterns and Related Methods for Precisely
Measuring Leakage Currents in Semiconductor Cell Transistors**

Examiner: Matthew C. Landau

Group Art Unit: 2815

Confirmation No.: 3015

Date: October 23, 2006

Mail Stop AMENDMENT

Commissioner for Patents

P.O. Box 1450

Alexandria, VA 22313-1450

AMENDMENT

Sir:

Applicants provide the present *Amendment* in response to the Office Action mailed August 1, 2006. It is not believed that an extension of time and/or additional fee(s), including fees for net addition of claims-are required, beyond those that may otherwise be provided for in documents accompanying this paper. In the event, however, that an extension of time is necessary to allow consideration of this paper, such an extension is hereby petitioned under 37 C.F.R. §1.136(a). Any additional fees believed to be due in connection with this paper may be charged to our Deposit Account No. 50-0220.